# Simbol-X calibration issues A. Moretti & G. Malaguti IACHEC Meeting, 2008

From the calibration point of view Simbol-x presents 3 main non-standard issues

- Focusing optics at very high energy (End2End)
- Mirror and detector are not rigidly connected (End2End)
- Very large focal length (the most critical, Mirror Module + End2End)

### Non-standard calibration: the energy band

Monochromatic energies in the 20-80 keV energy band

Few lines; mono-chromator (double crystal difractometer) is an option

Otherwise we could use only continuum



Figure 5. Line at nominal 30 keV obtained with the fixed-exit monochromator. See text.



Figure 6. Line at nominal 45 keV obtained with the fixed-exit monochromator. See text.

# Non-standard calibration: line of sight calibration



# Non-standard calibration: the focal length (studied by O.Citterio, S.Basso, D.Spiga)

Source finite distance problems (for large FL ~ 20m):

- A\_eff loss (single reflection)
- Parabola angle  $\neq$  hyperbola angle
- FP displacement
- Focal spot blurring

# **Problem 1: loss of effective area**



X-rays reflected near the parabola front-end do not undergo the reflection and are not focused on the X-ray detector this causes loss of effective area .

### **Problem 1: loss of effective area**



# **Problem 2: different incidence angle**



A source at infinity is focused by 2 reflections with the same angle  $\alpha$  (which is the angle between parabola and hyperbole)

A source at distance D has a divergence of  $\beta = R/D$  at the entrance of a mirror with radius R. The photon is reflected with 2 different angles  $\alpha+\beta$  on the parabola and  $\alpha-\beta$  on the hyperbole

Because  $\beta/\alpha \sim 4 x$  focal length/ source distance in the case of Simbol X at Panter this effect is not negligible

# **Problem 2: different incidence angle means different reflectivity**



W/Si graded multilayer,  $\alpha = 0.16 \text{ deg}$ 

The departure of the actual incidence angles from the nominal one has to be considered when interpreting the effective area data, as it changes significantly the measured reflectivity.

## **Other problems**

Increase of the focal length with respect to the nominal one:

$$f_1 = \frac{Df}{D - f}$$

D = distance mirror-source; e.g. f = 10 m,  $f_1 = 10.88 \text{ m}$ ,

 $f = 20 \text{ m}, f_1 = 24.44 \text{ m}$ 

#### A *slight* blurring of the image even at the focus $f_1$

$$HEW_D = 4\frac{L_p}{f} \tan\left[\alpha \left(\frac{f}{D}\right)^2\right]$$

$$L_p$$
 = length of the parabola,  $\alpha$  = nominal incidence angle;  
e.g.  $L_p$  = 30 cm, f =10 m,  $\alpha$  = 0.2 deg, HEW<sub>D</sub>= 0.6 arcsec  
e.g.  $L_p$  = 30 cm, f =20 m,  $\alpha$  = 0.2 deg, HEW<sub>D</sub>= 1.1 arcsec

# Solution for a single shell



If we adopt a pencil beam setup, we can select a thin beam (a few 10 arcsec divergence) and correct the beam divergence for a shell sector in order to make the two incidence angles equal (and equal to the on-axis incidence angle!)

Once the correct angles are set, all the optic performance (focusing + effective area) can be measured by spinning the optic around its axis, illuminating all sectors under the same conditions, and superposing all the images in the focal plane.

# Solution for the whole optical module: the jig



## End2End calibration dataset (the swift scheme)

#### DATASET:

· 20	energies
· 33	positions
$\cdot 10000$	photons





OUTPUT:

- · PSF Model
- $\cdot$  Effective Area
- $\cdot$  Energy resolution
- $\cdot$  ARF + RMF

with 5% of accuracy

## Standard calibration IIa: the PSF calibration





Assuming a King profile A speculation more than a simulation....



### Standard calibration IIb: HEW verification



Given ~10000 counts, the accuracy in the HEW measurement is < 5%

Assuming a King profile: A speculation more than a simulation....





# **PSF model importance**



For SIMBOL-X the situation is very different: it will collect photons over a wide energy band. Therefore the PSF calibration as function of energy will be very important.

# SWIFT XRT PSF in orbit

2 different sources, with different spectra and off-axis angle , but same



For XRT It is very easy to model the off-axis angle and energy dependence, because this dependence is very shallow

## Standard calibration: effective area



~10000 counts, ch energy the statistical uncertainties in the effective are ~ 1%

we have to take into account:

ures between calibration energies ertainties in the input spectrum and count rate

# Swift-XRT Effective area from ground to orbit



# **TIMING REQUIREMENTS**

Total time = N\_ene \* N\_pos \* counts / rate@ccd+[ N\_ene \* dt\_ene + N\_pos \*dt\_pos] N\_en. =20 N\_pos=33 counts=10000 rate\_at\_ccd =1000.

- → total time [**standard**] = 2 hrs + dead time
- → total time [**pencil beam**] = 100\*(total standard time) = 200 hrs + dead time pencil beam
- → total time [relative position] = 5\*(total pencil beam) = 1000 hrs + dead time relative position

## **In-flight Calibration**



# DA calibration (model) philosophy

What (model)	Why (Goal)	When	
Breadboard	EMI/EMC compatibility tests	End 2008	
Demonstrator	Separated chains functionality validation	End 2009	
SM	Structural validation	2008-2009	
STM	Mechanical, thermal and integration validation	2009-2010	
EM	Electrical design validation	mid-2010	
QM	Qualification	2011	
FM	Fly	2012	

# MU calibration (model) philosophy

What (model)	Why (Goal)	What	When
STM	Optical validation after Mechanical & thermal cycles	4 "standard" + 96 dummy shells	End 09
QM	Scientific performance validation	10 "standard" shells + 90 "dummy" shells	11
FM	Fly		12